## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	09/705,101
Filing Date	November 2, 2000
Inventor	Segal et al.
Assignee	eywell International Inc.
Group Art Unit	1742
Examiner	Ip, Sikyin
Attorney's Docket No	30-5076(4015)
Title: Physical Vapor Deposition Targets, and Methods of Fabric	ating Metallic Materials

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: June 5 Stuff

Jennifer J. Taylor, Ph.D

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Sheet I of I Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SERIAL NO. 09/705,101 ATTY. DOCKET NO. 30-5076(4015) LIST OF ART CITED BY APPLICANT APPLICANT Vladimir Segal et al. (Use several sheets if necessary) FILING DATE GROUP November 2, 2000 1742 U.S. PATENT DOCUMENTS Date Class Subclass \*Examiner Document Name Filing Date Initial Number If Appropriate AA ΑB AC AD OFFICE OF PETITIONS ΑE ΑF AG ΑH ΑĪ ΑJ ΑK AL FOREIGN PATENT DOCUMENTS Document Date Class Subclass Country Translation Number Yes No AM ΑN ΑO ΑP AQ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AR R.Z. Valiev et al., "Plastic deformation of alloys with submicron-grained structure", Materials Science and Engineering, A137 (1991) pp.

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R.Z. Valiev et al., "Plastic deformation of alloys with submicron-grained structure", Materials Science and Engineering, A137 (1991) pp 35-40.

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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE CONSIDERED

**EXAMINER**